PCN Number:	201703080	20170308001					PCN Date:		Mar 9 2017	
Title: Qualification of an updated BOM for the THS788PFD										
Customer Contact: PCN Man			nager Dept: Quality Services		ces					
Proposed 1 st Ship Date: Ju		June 9	une 9 2017		Estimated Sample Date provided a Availability: sample request			•		
Change Type:										
Assembly Si		☐ De	esign			Wafer Bump Site				
Assembly Process			☐ Da	Data Sheet			Wafer Bump Material			
Assembly Materials				Part number change			Wafer Bump Process			
Mechanical S	•	_	=	Test Site			Wafer Fab Site			
Packing/Shipping/Labeling			Te	Test Process			Wafer Fab Materials			
						L	Wafe	Wafer Fab Process		
PCN Details										
Description of (Change:									
This notification is to announce the qua follows: What Mount Compound Leadframe finish			Current 4206201 NiPdAu				New 4206895 NiPdAu (Roughened)			
	Reason for Change:									
Improved material set										
Anticipated impact on Form, Fit, Function, Quality or Reliability (positive / negative):										
None										
Anticipated impact on Material Declaration										
No Impact to the Material Declarations or Product Content reports are driven from production data and will be available following the production release. Upon production release the revised reports can be obtained from the TI ECO website.						roduction				
Changes to product identification resulting from this PCN:										
None										
Product Affected:										
THS788PFD THS788PFDT										



Qualification Report

THS788PFD with Roughened Leadframe & 4206895 mount-compound Approve Date 21-Nov-2016

Product Attributes

Attributes	Qual Device: THS788PFD	QBS Process Reference: TRF1016GQS	QBS Package Reference: DS58C20IPFP_SSTN	QBS Package Reference: S106049BC1PZP
Assembly Site	TAI	HIJI	PHI	TAI
Package Family	HTQFP	JRBGA	HTQFP	TQFP
Flammability Rating	-	UL 94 V-0	UL 94 V-0	UL 94 V-0
Wafer Fab Supplier	FFAB	FFAB	DMOS5	DM0S5
Wafer Process	RFSIGE	RFSIGE1	1833C05	LBC8- DT

⁻ QBS: Qual by Similarity

Qualification Results

Data Displayed as: Number of lots / Total sample size / Total failed

Туре	Test Name / Condition	Duration	Qual Device: THS788PFD	QBS Process Reference: TRF1016GQS	QBS Package Reference: ADS58C20IPFP_SSTN	QBS Package Reference: S106049BC1PZP
AC	Autoclave 121C	96 Hours	-	3/231/0	3/231/0	3/231/0
ED	Electrical Distributions	Cpk>1.67 Room, hot, and cold test	-	-	-	1/90/0
ELFR	Early Life Failure Rate, 125C	48 Hours	-	-	-	2/1600/0
ED	Electrical Characterization	Per Datasheet Parameters	-	Pass	-	-
HAST	Biased Hast, 130C/85%RH	96 Hours	-	3/230/0	-	2/154/0
HBM	ESD - HBM	1500 V	-	-	-	1/3/0
CDM	ESD - CDM	250 V	1/3/0	-	-	-
HTOL	Life Test ,140C	480 Hours	-	3/231/0	-	-
HTOL	Life Test, 125C	1000	-	-	-	3/229/0
HTSL	High Temp. Storage Bake, 170C	420 Hours	-	-	3/231/0	-
HTSL	High Temp. Storage Bake, 175C	175C, 500 hours	-	-	-	1/50/0
LU	Latch-up	(per JESD78)	-	1/6/0	-	1/6/0
TC	Temperature Cycle, -55/125C	500 Cycles	-	3/220/0	-	-
TC	Temperature Cycle, -65/150C	500 Cycles	1/77/0	-	3/231/0	3/231/0
TS	Thermal Shock, -65/150C	500 Cycles	-	3/229/0	-	-

Green/Pb-free Status:

Qualified Pb-Free(SMT) and Green

For questions regarding this notice, e-mails can be sent to the regional contacts shown below or your local Field Sales Representative.

Location	E-Mail
USA	PCNAmericasContact@list.ti.com
Europe	PCNEuropeContact@list.ti.com
Asia Pacific	PCNAsiaContact@list.ti.com
Japan	PCNJapanContact@list.ti.com

⁻ Qual Device THS788PFD is qualified at Not Classified

Preconditioning was performed for Autoclave, Unbiased HAST, THB/Biased HAST, Temperature Cycle, Thermal Shock, and HTSL, as applicable

- The following are equivalent HTOL options based on an activation energy of 0.7eV: 125C/1k Hours, 140C/480 Hours, 150C/300 Hours, and 155C/240 Hours

- The following are equivalent HTSL options based on an activation energy of 0.7eV: 150C/1k Hours, and 170C/420 Hours

- The following are equivalent Temp Cycle options per JESD47: -55C/125C/700 Cycles and -65C/150C/500 Cycles

Quality and Environmental data is available at TI's external Web site: http://www.ti.com/